Application/Control No. Applicant(s)/Patent Under Reexamination 10/070,534 TETSUKAZU HUKUHARA ET AL Notice of References Cited Examiner Art Unit Page 1 of 1 Deborah Yee 1742 **U.S. PATENT DOCUMENTS** Document Number Date Name Classification Country Code-Number-Kind Code MM-YYYY US-Α US-В US-С D US-US-Ε US-F US-G USн US-US-J US-Κ US-L US-М FOREIGN PATENT DOCUMENTS **Document Number** Date Country Code-Number-Kind Code Country Name Classification MM-YYYY 2002-282982 10-2002 Japan Sakata, Shinji et al N C 2002-285231 10-2002 0 Japn Sakata, Shinji et al Ρ Q R s Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U ٧ W

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